ABSTRACT OF THE DISCLOSURE

Apparatus And Method For Handling An Integrated Circuit

An apparatus (100) and method are provided for picking up an integrated circuit (156) and for facilitating the optical testing thereof. The apparatus (100) comprises a pick-up mechanism that includes a vacuum chamber (105). The vacuum chamber (105) is defined by an upper portion (106), an expandable member (109), and a lower portion (113). The lower portion (113) defines a suction orifice (139) that is moveable with a movement of the expandable member (109). An optical pathway (159) is defined by the vacuum chamber (105), the optical pathway (159) passing through the suction orifice (139) and onto an integrated circuit (156) that is held against the suction orifice (139) via a vacuum pressure applied to the vacuum chamber (105).

Figure 1